# ANNAMACHARYA INSTITUTE OF TECHNOLOGY & SCIENCES::KADAPA (AUTONOMOUS)

Approved by AICTE, New Delhi & Affiliated to JNTUA, Ananthapuramu Accredited by NBA (B.Tech-EEE, ECE & CSE) & NAAC with 'A' Grade Utukur (Post), C.K. Dinne (V&M), Kadapa, YSR (Dist) Andhra Pradesh - 516 003

## Department of Electronics & Communication Engineering M.Tech. IN VLSI System Design

Effective for the batches admitted from 2023-24

### **SEMSTER - III**

S.No.	Course	Course Name	Cate	Hou	rs per	r	Credits
	codes		gory	L	Т	Р	
1.	23HPE5713 23HPE5714 23HPE5715	<b>Program Elective – V</b> Bi-CMOS Technology and Applications Optimization Techniques and Applications in VLSI Design SoC Architecture	PE	3	0	0	3
2.	23HOE0301 23HOE1E01 23HOE0302	<b>Open Elective</b> Industrial Safety Business Analytics Waste to Energy	OE	3	0	0	3
3.	23HPR5701	Dissertation Phase – I	PR	0	0	20	10
4.	23HCA5701	Co-curricular Activities					2
	•	Tot al	-				18

### **SEMESTER - IV**

S.No.	Course	Course Name	Category	Ho	urs p	er	Credits
	codes			L	Т	Р	
1.	23HCA5702	Dissertation Phase – II	PR	0	0	32	16
		Total					16

Course Code	BICMOS TECHNOLOGY AND APPLICATIONS		T	P	(
23HPE5713	Program Elective – V	3	0	0	3
	Semester		Π	I	
Course Objective					
	nonstrate in-depth knowledge in BiCMOS Technology.		·	~	~~~
	lyze complex engineering problems critically for conducting rese	earch	in Bi	СМС	5
Techn	6,				
	ve engineering problems with wide range of solutions in Radio Freated circuits.	equen	сy		
-	ize different digital circuits using BiCMOS Technology				
	(CO): Student will be able to				
	strate in-depth knowledge in BiCMOS Technology.				
	ze complex engineering problems critically for conducting rese	arch	in Bi	СМО	)S
Techn					
	engineering problems with wide range of solutions in Radio Free	juenc	y Inte	grat	ed
circuit		-		-	
	e different digital circuits using BiCMOS Technology				
UNIT - I			ture H		
	s Technology: CMOS Process Technology, Bipolar Process Tech		gy, Is	olati	or
*	oolar Technologies, BiCMOS Technology, BiCMOS Design Rul	es.			
UNIT - II			ture H		
	onsiderations: Design Considerations for MOSFET's, Design C	onsid	eratio	ons f	or
	rs, BiCMOS Device Design Considerations.				
UNIT - III	Scaling: MOS Device Scaling, Bipolar Device Scaling.	Lag	ture H	Inci	
	: Modeling of the MOS Transistor: MOSFET Structure and O				٦F
	DS Transistor, Analytical Model for Short-Channel MOS Devices	-	uon,	SIR	
	Sipolar Transistor: BJT Structure and Operation, Ebers-Moll Mod		polar		
Models in SPICE.		,	r		
UNIT - IV		Lec	ture H	Irs:	
<b>BiCMOS Digital</b>	Integrated Circuits: BiMOS Totem-Pole Inveter: DC Character	eristic	s, Tra	ansie	nt
	ependence on the Device Parameters, BiCMOS Circuit Design, C	Comp	aring	CM	DS
	erters Speed, BiCMOS Gates.				
UNIT - V			ture H		
	al Circuit Applications: Adders, Multiplier, Random	Acces	ss N	lemo	ory
	gic Arrays, BiCMOS Logic Cells, BiCMOS Gate Arrays.				
Textbooks:			<b>. .</b> .		1
	ubabi, AbdellatifBellaouar& Mohamed I. Elmasry "Digital BiC	-MO:	s Inte	egrat	ed
	pringer Science+ BusÎness Media, LLC. , BICMOS Technology & Applications, Kluwer Academic Publisł	nere			
Reference Books:		1013.			
		Edu	ontion		
	Samir S. Rofail, Wang-Ling Goh, CMOS/BiCMOS ULSI, Pearson	1 6/11/4			
1. Kiat-Seng yeo,	Samir S. Rofail, Wang-Ling Goh, CMOS/BiCMOS ULSI, Pearson Denis P. Galipeau, Analog BiCMOS Design: Practices & Pitfalls.				
1. Kiat-Seng yeo, S 2. James C. Daly,	Samir S. Rofail, Wang-Ling Goh, CMOS/BiCMOS ULSI, Pearson Denis P. Galipeau, Analog BiCMOS Design: Practices & Pitfalls, 1gen, Johan Huijsing, Compact Low-Voltage and High-Speed (	CRC	Press	5	)S

Course Code	OPTIMIZATION TECHNIQUES AND APPLICATIONS		T	<u>P</u>	(
3HPE5714	IN VLSI DESIGN (Program Elective – V)	3	0	0	3
	Semester		II	l	
Course Objectiv					
Course Objectiv					
	rstand basics of statistical modeling				
	zze performance of CMOS circuits with respect to power, area and sp		• .		c
-	ire complete knowledge regarding the various algorithms used for	optii	nızat	ion (	)İ
power a					
	es (CO): Student will be able to				
	and basics of statistical modeling				
•	performance of CMOS circuits with respect to power, area and spee				0
-	complete knowledge regarding the various algorithms used for	optin	nızatı	on c	t
power a	nd area	<b>T</b> .		r	
UNIT - I			ure H		
	deling: Modeling sources of variations, Monte Carlo tech	-			
	ling-Pelgrom's model, Principle component based modeling,				
	rmance modeling- Response surface methodology, delay modeli	1ng, 1	nterc	onne	ct
delay models.		-		-	
UNIT - II			ure H		
	ormance, Power and Yield Analysis: Statistical timing analysis, j			-	
technique Dar	racian naturaliza Lagiraga madala Lligh larval statistical and	- 1 : -	C - +	alaı	
1		arysis	, Gat		<i>v</i> e
statistical analys	sis, dynamic power, leakage power, temperature	•	, Gat 1d	pov	
		aı	nd	pov	
statistical analys supply variation UNIT - III	sis, dynamic power, leakage power, temperature s, High level yield estimation and gate level yield estimation.	aı Lect	nd ure H	pov [rs:	ve
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Course Code	SoC ARCHITECTURE		T	P	
23HPE5715	Program Elective – V	3	0	0	
Comme Ohiosti	Semester		II	L	
Course Objecti		1.	<u> </u>	<u> </u>	
	erstand the basics related to SoC arch and different approaches relat	ted to	SoCI	Desig	;n.
	et an appropriate robust processor for SoC Design				
	at an appropriate memory for SoC Design.				
	ze real time case studies				
	tes (CO): Student will be able to				
	and the basics related to SoC archi & different approaches related	d to S	SoCD	esign	1.
	n appropriated robust processor for SoC Design				
	n appropriate memory for SoC Design.				
	real time case studies				
UNIT - I			ture I		
	the System Approach: System Architecture, Components of the system				
	ocessor Architectures, Memory &Addressing. System level interco	on eq	ction,	An	
	OC Design, System Architecture and Complexity.	I			
UNIT - II			ture H		
	roduction, Processor Selection for SOC, Basic concepts in Processo				
	in Processor Microarchitecture, Basic elements in Instruction han			ffers:	
	beline Delays, Branches, More Robust Processors, Vector Processo	ors ar	nd		
	tion extensions, VLIW Processors, Superscalar Processors				
UNIT - III			ture H	Irs:	
• •	n for SOC: Overview: SOC external memory, SOC Internal Memo	•			
	d Cache memory, Cache Organization, Cache data, Write Policies,			s for	
	nt at miss time, Other Types of Cache, Split – I, and D – Caches, M		evel		
	Memory System, Models of Simple Processor – memory interaction				
UNIT - IV			ture F	Irs:	
	ustomization and Configurability: Interconnect Architectures, Bus:				
Architectures, S	OC Standard Buses, Analytic Bus Models, Using the Bus model,	Effec	ts of	Bus	
	• • •				
	l contention time.				
SOC Customi	l contention time. zation: An overview, Customizing Instruction Processor, Recon				
SOC Customi Technologies, 1	l contention time. <b>zation:</b> An overview, Customizing Instruction Processor, Recon Mapping design onto Reconfigurable devices, Instance- Specific	desi	gn,		
<b>SOC Customi</b> Technologies, 1 Customizable S	l contention time. <b>zation:</b> An overview, Customizing Instruction Processor, Recon Mapping design onto Reconfigurable devices, Instance- Specific oft Processor, Reconfiguration - overhead analysis and trade-off ar	desi	gn,		
<b>SOC Customi</b> Technologies, 1 Customizable S reconfigurable H	l contention time. <b>zation:</b> An overview, Customizing Instruction Processor, Recon Mapping design onto Reconfigurable devices, Instance- Specific oft Processor, Reconfiguration - overhead analysis and trade-off ar	desi nalys	gn, is on		
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SOC Customi Technologies, 1 Customizable S reconfigurable F UNIT - V Application Stu	I contention time. <b>zation:</b> An overview, Customizing Instruction Processor, Recon Mapping design onto Reconfigurable devices, Instance- Specific oft Processor, Reconfiguration - overhead analysis and trade-off an Parallelism. <b>dies / Case Studies:</b> SOC Design approach; AES-algorithms, Design	desi nalys Lect	gn, is on ture H		
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SOC Customi Technologies, 1 Customizable S reconfigurable I UNIT - V Application Stu Image compre- Textbooks: 1. Computer Sy 2. ARM Syster Professional Reference Bool 1. Design of Sy 2.Co-Verification (EmbeddedTec)	l contention time. zation: An overview, Customizing Instruction Processor, Recon Mapping design onto Reconfigurable devices, Instance- Specific oft Processor, Reconfiguration - overhead analysis and trade-off ar Parallelism. dies / Case Studies: SOC Design approach; AES-algorithms, Design ssion–JPEG compression. stem Design System-on-Chip - Michael J. Flynn and Wayne Luk, n on Chip Architecture – Steve Furber, 2ndEdition, 2000, Addison stem on a Chip: Devices and Components – Ricardo Reis, 1st Ed., on of Hardware and Software for ARM System on mology) – Jason Andrews – Newnes, BK and CDROM.	e desi nalys Lect and e Wiel n We 2004 n C	gn, is on ture H evaluate ly Inc sley , Spr hip	ition; lia Pr inger Des	ig
SOC Customi Technologies, 1 Customizable S reconfigurable F UNIT - V Application Stu Image compre Textbooks: 1. Computer Sy 2. ARM System Professional Reference Bool 1. Design of Sy 2.Co-Verification (EmbeddedTech 3.System on Ch	l contention time. zation: An overview, Customizing Instruction Processor, Recon Mapping design onto Reconfigurable devices, Instance- Specific oft Processor, Reconfiguration - overhead analysis and trade-off ar Parallelism. dies / Case Studies: SOC Design approach; AES-algorithms, Design ssion–JPEG compression. stem Design System-on-Chip - Michael J. Flynn and Wayne Luk, n on Chip Architecture – Steve Furber, 2ndEdition, 2000, Addison ss: stem on a Chip: Devices and Components – Ricardo Reis, 1st Ed., on of Hardware and Software for ARM System on	e desi nalys Lect and e Wiel n We 2004 n C	gn, is on ture H evaluate ly Inc sley , Spr hip	ition; lia Pr inger Des	ig

# **OPEN ELECTIVE**

Course Code	INDUSTRIAL SAFETY	L	Т	Р	С
23HOE0301		3	0	0	3
	Semester			Ш	
Course Objective					
	bout Industrial safety programs and toxicology, Industrial laws , reg	ulat	ions a	and so	ource
models			.1 1		
	tand about fire and explosion, preventive methods, relief and its sizin	ig m	ethod	S	
	e industrial hazards and its risk assessment.				
	(CO): Student will be able to				
	important legislations related to health, Safety and Environment. requirements mentioned in factories act for the prevention of accident	nta			
	tand the health and welfare provisions given in factories act.	ms.			
UNIT - I	and the health and wentare provisions given in factories act.	La	cture	Ure.	
	Accident, causes, types, results and control, mechanical and elec				truess
	tive steps/procedure, describe salient points of factories act 1948				
	king water layouts, light, cleanliness, fire, guarding, pressure vesse				
	ation and firefighting, equipment and methods.	, <b>·</b>	, 5	arety	00101
UNIT - II		Leo	cture	Hrs	
	naintenance engineering: Definition and aim of maintenance engin				rv and
	ons and responsibility of maintenance department, Types of main				
	ols used for maintenance, Maintenance cost & its relation with re				
Service life of equ		P1	• • • • •		, nonij,
UNIT - III		Leo	cture	Hrs:	
Wear and Corrosi	on and their prevention: Wear- types, causes, effects, wear reduction				ricants-
	tions, Lubrication methods, general sketch, working andapplicat				
	ssure grease gun, iii. Splash lubrication, iv. Gravity lubrication, v. V				
	ication, vii. Ring lubrication, Definition, principle and factors af				
	n, corrosion prevention methods.				
UNIT - IV			cture		
	It tracing-concept and importance, decision treeconcept, need and a				
	activities, show as decision tree, draw decision tree for problem				
	atic, automotive, thermal and electrical equipment's like, I. Any				
	pressor, iv. Internal combustion engine, v. Boiler, vi. Electrical mot	ors,	Туре	s of f	aults in
machine tools and					
	their general causes.	т.,		II	
UNIT - V			cture		·
UNIT - V Periodic and pre	ventive maintenance: Periodic inspection-concept and need, degr	reas	ing,	clean	
UNIT - V Periodic and pre repairing scheme	ventive maintenance: Periodic inspection-concept and need, degrees, overhauling of mechanical components, overhauling of electric	reas rical	ing, mot	clean tor, c	ommor
UNIT - V Periodic and pre repairing scheme troubles and rem	ventive maintenance: Periodic inspection-concept and need, degr s, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definit	reas rical tion,	ing, mot	clean tor, c d, st	ommor eps and
UNIT - V Periodic and pre repairing scheme troubles and rem advantages of pro-	ventive maintenance: Periodic inspection-concept and need, degr s, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definit eventive maintenance. Steps/procedure for periodic and preventive	reas rical tion, ve n	ing, mot nee naint	clean tor, c d, st enanc	ommor eps and e of: I
UNIT - V Periodic and pre repairing scheme troubles and rem advantages of pr Machine tools, ii.	ventive maintenance: Periodic inspection-concept and need, degr s, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definit eventive maintenance. Steps/procedure for periodic and preventive Pumps, iii. Air compressors, iv. Diesel generating (DG) sets, Progr	reas rical tion, ve n	ing, mot nee naint and s	clean tor, c d, st enanc ched	commor eps and ce of: I ule of
UNIT - V Periodic and pre repairing scheme troubles and rem advantages of pr Machine tools, ii. preventive mainte	ventive maintenance: Periodic inspection-concept and need, degr s, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definit eventive maintenance. Steps/procedure for periodic and preventive Pumps, iii. Air compressors, iv. Diesel generating (DG) sets, Progr enance of mechanical and electrical equipment, advantages of pre	reas rical tion, ve n	ing, mot nee naint and s	clean tor, c d, st enanc ched	commor eps and ce of: I ule of
UNIT - V Periodic and pre repairing scheme troubles and rem advantages of pr Machine tools, ii. preventive mainte Repair cycle conc	ventive maintenance: Periodic inspection-concept and need, degr s, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definit eventive maintenance. Steps/procedure for periodic and preventive Pumps, iii. Air compressors, iv. Diesel generating (DG) sets, Progr	reas rical tion, ve n	ing, mot nee naint and s	clean tor, c d, st enanc ched	common eps and ce of: I ule of
UNIT - V Periodic and pre repairing scheme troubles and rem advantages of pr Machine tools, ii. preventive mainte Repair cycle conc Textbooks:	ventive maintenance: Periodic inspection-concept and need, degrees, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definite eventive maintenance. Steps/procedure for periodic and preventive Pumps, iii. Air compressors, iv. Diesel generating (DG) sets, Programance of mechanical and electrical equipment, advantages of preept and importance	reas rical tion, ve n	ing, mot nee naint and s	clean tor, c d, st enanc ched	common eps and ce of: I ule of
UNIT - V Periodic and pre repairing scheme troubles and rem advantages of pro Machine tools, ii. preventive mainte Repair cycle conce <b>Textbooks:</b> 1. Maintenance En	ventive maintenance: Periodic inspection-concept and need, degr s, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definit eventive maintenance. Steps/procedure for periodic and preventive Pumps, iii. Air compressors, iv. Diesel generating (DG) sets, Progr enance of mechanical and electrical equipment, advantages of pre	reas rical tion, ve n	ing, mot nee naint and s	clean tor, c d, st enanc ched	common eps and ce of: I ule of
UNIT - V Periodic and pre repairing scheme troubles and rem advantages of pr Machine tools, ii. preventive mainte Repair cycle conce Textbooks: 1. Maintenance En 2. Maintenance En Reference Books:	ventive maintenance: Periodic inspection-concept and need, degr s, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definit eventive maintenance. Steps/procedure for periodic and preventiv Pumps, iii. Air compressors, iv. Diesel generating (DG) sets, Progr enance of mechanical and electrical equipment, advantages of pre ept and importance gineering Handbook, Higgins & Morrow, Da Information Services. gineering, H. P. Garg, S. Chand and Company.	reas rical tion, ve n	ing, mot nee naint and s	clean tor, c d, st enanc ched	commor eps and ce of: I ule of
UNIT - V Periodic and pre repairing scheme troubles and rem advantages of pr Machine tools, ii. preventive mainte Repair cycle conce Textbooks: 1. Maintenance En 2. Maintenance En Reference Books: 1. Pump-hydraulic	ventive maintenance: Periodic inspection-concept and need, degr s, overhauling of mechanical components, overhauling of electric edies of electric motor, repair complexities and its use, definite eventive maintenance. Steps/procedure for periodic and preventive Pumps, iii. Air compressors, iv. Diesel generating (DG) sets, Progression enance of mechanical and electrical equipment, advantages of pre ept and importance	reas rical tion, ve n	ing, mot nee naint and s	clean tor, c d, st enanc ched	common eps and ce of: I ule of

<b>Course Code</b>	BUSINESS ANALYTICS	L	۲	T	P	С
23HOE1E01		3		0	0	3
	Semester				III	
<b>Course Objective</b>	s:					
	objective of this course is to give the student a comprehensive under	star	ndiı	ng c	of	
business a	analytics methods.					
<b>Course Outcomes</b>	s (CO): Student ill be able to					
	vill demonstrate knowledge of data analytics.					
	will demonstrate the ability of think critically in making decisions ba	sed	on			
	leep analytics.					
	will demonstrate the ability to use technical skills in predicative and					
	ve modeling to support business decision-making.	-1-4	_			
• Students v	will demonstrate the ability to translate data into clear, actionable insi	<u>~</u>		1nc <sup>1</sup>	Hrs:	
	- Our minue of Duringers Anglasia Oramium of Deminue at D					·
Analyst.	s: Overview of Business Analysis, Overview of Requirements, R	loie	01	the	Bus	iness
	project team, management, and the front line, Handling Stakeholder	Con	flic	ote		
UNIT - II	project team, management, and the nont mile, manufing stakeholder				Hrs:	
	ems Development Life Cycles, Project Life Cycles, Product Life C	1				nent
Life Cycles.	this Development Life Cycles, 110ject Life Cycles, 110ddet Life C	yen	.5, 1	Reg	lanci	nem
UNIT - III		L	ectr	ire ]	Hrs:	
Requirements, Re Documents.Trans Additive/Subtract Flowcharts, Entit Modeling, Busine	ements: Overview of Requirements, Attributes of Good Requ quirement Sources, Gathering Requirements from Stakeholders, Co forming Requirements: Stakeholder Needs Analysis, Decon ive Analysis, Gap Analysis, Notations (UML & BPMN), Flowchar y-Relationship Diagrams, State-Transition Diagrams, Data Flow ess Process Modeling	omm npo rts	non ositi Sw:	Re ion im	equire Ana Lane	ement alysi
UNIT - IV		Le	ectu	ire ]	Hrs:	
	ements: Presenting Requirements, Socializing Requirements and C rements. Managing Requirements Assets: Change Control, Require					ance,
UNIT - V		Le	ectu	ire ]	Hrs:	
Storytelling and I	: Embedded and colleborative business intelligence, Visual data Data Journalism.	i re	:00	very	7, Da	ıta
Textbooks:						
	sis by James Cadle et al. ment: The Managerial Process by Erik Larson and, Clifford Gray					
<b>Reference Books:</b>						
Schnieder	analytics Principles, Concepts, and Applications by Marc J. Schniede jans, Christopher M. Starkey, Pearson FT Press. Analytics by James Evans, persons Education.	rjar	1s, I	Dar	a G.	

Course Code	WASTE TO ENERGY	L	Т	P	C
3HOE00302		3	0	0	3
	Semester	III			
Course Objective	s:				
<ul> <li>Introduce</li> </ul>	and explain energy from waste, classification and devices to conv	ert w	vaste	to	
energy.					
<ul> <li>To impart</li> </ul>	knowledge on biomass pyrolysis, gasification, combustion and con	nvers	sion p	proces	ss.
• To educat	e on biogas properties ,bio energy system, biomass resources and	their	class	sifica	tion
and biom	ass energy programme in India.				
<b>Course Outcomes</b>	s (CO): Student will be able to				
To know a	about overview of Energy to waste and classification of waste.				
• To acquir	e knowledge on bio mass pyrolysis, gasification, combustion and c	onve	ersio	n pro	cess
in detail.					
-	nowledge on properties of biogas, biomass resources and progra	mme	es to	conv	ert
	energy in India.				
UNIT - I				Hrs:1	
	nergy from Waste: Classification of waste as fuel - Agro base	d, Fo	orest	resid	lue,
	MSW – Conversion devices – Incinerators, gasifiers, digestors				
UNIT - II				Hrs:1	
	s: Pyrolysis – Types, slow fast – Manufacture of charcoal – I	Meth	ods	- Yie	lds
and application –	Manufacture of pyrolytic oils and gases, yields and applications.				
UNIT - III		Leo	cture	Hrs:1	2
	tion: Gasifiers – Fixed bed system – Downdraft and updraft gasif				
bed gasifiers – De	sign, construction and operation - Gasifier burner arrangement fo	r the	rmal	heat	ng
	e arrangement and electrical power - Equilibrium and kinet	ic co	nsid	eratic	n
in gasifier operati	on	_			
UNIT - IV				Hrs:1	
	tion: Biomass stoves – Improved chullahs, types, some exotic d				
	s, inclined grate combustors, Fluidized bed combustors, Design,	cons	struct	tion a	ind
	tion of all the above biomass combustors.	т	4	TT 1	0
UNIT - V				Hrs:1	-
	s of biogas (Calorific value and composition) - Biogas plan				
classification -	gy system - Design and constructional features - Biomass re-	esour	ces	and	iner
	ion processes - Thermo chemical conversion - Direct comb	meti	on	hior	naci
	lysis and liquefaction - biochemical conversion - anaerobic dig				
	pplications - Alcohol production from biomass - Bio diesel p				30
	nergy conversion - Biomass energy programme in India.	iout			
Textbooks:					
	rentional Energy, Desai, Ashok V., Wiley Eastern Ltd., 2018				
	echnology - A Practical Hand Book - Khandelwal, K. C. and Mahd	i. S	S., 1	гмн	
2. Diogas IX 2017		.,	S., 1		
Reference Books:					
	d and Fuel from Biomass, Challal, D. S., IBH Publishing Co. Pvt. 1	Ltd.	1991		
	Conversion and Technology, C. Y. WereKo-Brobby and E. B. H				ilev
& Sons, 1		0			